



High-end Power Semiconductor Manufacturer

KP1500A 1000V-1800V

Phase Control Thyristor

- High power cycling capability
- Low on-state and switching losses
- Designed for traction and industrial applications



Mean on-state current			I_{TAV}	1500 A		
Repetitive peak off-state voltage			V_{DRM}	1000 – 1800 V		
Repetitive peak reverse voltage			V_{RRM}			
Turn-off time			t_q	160 μ s		
V_{DRM}, V_{RRM}, V	1000	1200	1400	1600	1800	
Voltage code	10	12	14	16	18	
$T_{vj}, ^\circ C$	-60 – 125					

MAXIMUM ALLOWABLE RATINGS

Symbols and parameters		Units	Values	Test conditions	
ON-STATE					
I_{TAV}	Mean on-state current	A	1500	$T_c=85^\circ\text{C}$, Double side cooled 180° half-sine wave; 50 Hz	
I_{TRMS}	RMS on-state current	A	2355	$T_c=85^\circ\text{C}$, Double side cooled 180° half-sine wave; 50 Hz	
I_{TSM}	Surge on-state current	kA	28.0 32.0	$T_j=T_{j\max}$ $T_j=25^\circ\text{C}$	180° half-sine wave; 50 Hz ($t_p=10\text{ ms}$); single pulse; $V_D=V_R=0\text{ V}$; Gate pulse: $I_G=2\text{ A}$; $t_{GP}=50\text{ }\mu\text{s}$; $di_G/dt\geq 1\text{ A}/\mu\text{s}$
			30.0 35.0	$T_j=T_{j\max}$ $T_j=25^\circ\text{C}$	180° half-sine wave; 60 Hz ($t_p=8.3\text{ ms}$); single pulse; $V_D=V_R=0\text{ V}$; Gate pulse: $I_G=2\text{ A}$; $t_{GP}=50\text{ }\mu\text{s}$; $di_G/dt\geq 1\text{ A}/\mu\text{s}$
I^2t	Safety factor	$\text{A}^2\text{s}\cdot 10^3$	3920 5120	$T_j=T_{j\max}$ $T_j=25^\circ\text{C}$	180° half-sine wave; 50 Hz ($t_p=10\text{ ms}$); single pulse; $V_D=V_R=0\text{ V}$; Gate pulse: $I_G=2\text{ A}$; $t_{GP}=50\text{ }\mu\text{s}$; $di_G/dt\geq 1\text{ A}/\mu\text{s}$
			3735 5080	$T_j=T_{j\max}$ $T_j=25^\circ\text{C}$	180° half-sine wave; 60 Hz ($t_p=8.3\text{ ms}$); single pulse; $V_D=V_R=0\text{ V}$; Gate pulse: $I_G=2\text{ A}$; $t_{GP}=50\text{ }\mu\text{s}$; $di_G/dt\geq 1\text{ A}/\mu\text{s}$
BLOCKING					
V_{DRM}, V_{RRM}	Repetitive peak off-state and Repetitive peak reverse voltages	V	1000 – 1800	$T_{j\min} < T_j < T_{j\max}$; 180° half-sine wave; 50 Hz; Gate open	
V_{DSM}, V_{RSM}	Non-repetitive peak off-state and Non-repetitive peak reverse voltages	V	1100 – 1900	$T_{j\min} < T_j < T_{j\max}$; 180° half-sine wave; 50 Hz;single pulse; Gate open	
V_D, V_R	Direct off-state and Direct reverse voltages	V	$0.75\cdot V_{DRM}$ $0.75\cdot V_{RRM}$	$T_j=T_{j\max}$; Gate open	

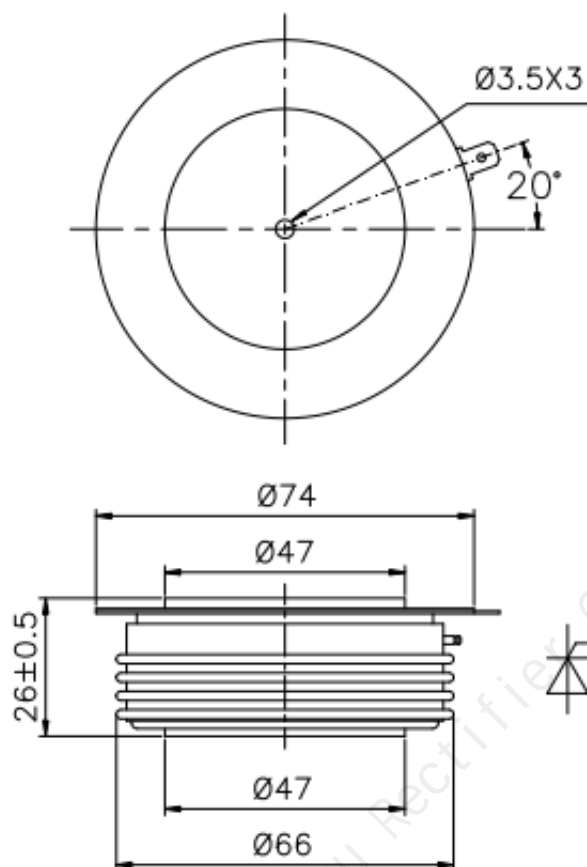
TRIGGERING				
I_{FGM}	Peak forward gate current	A	8	$T_j = T_{j\max}$
V_{RGM}	Peak reverse gate voltage	V	5	
P_G	Gate power dissipation	W	4	$T_j = T_{j\max}$ for DC gate current
SWITCHING				
$(di_T/dt)_{crit}$	Critical rate of rise of on-state current non-repetitive ($f=1\text{ Hz}$)	A/ μs	1000	$T_j = T_{j\max}$; $V_D = 0.67V_{DRM}$; $I_{TM} = 2 I_{TAV}$; Gate pulse: $I_G = 2\text{ A}$; $t_{GP} = 50\text{ }\mu\text{s}$; $di_G/dt \geq 1\text{ A}/\mu\text{s}$
THERMAL				
T_{stg}	Storage temperature	$^{\circ}\text{C}$	-60 – 125	
T_j	Operating junction temperature	$^{\circ}\text{C}$	-60 – 125	
MECHANICAL				
F	Mounting force	kN	24.0 – 28.0	
a	Acceleration	m/s^2	50 100	Device unclamped Device clamped

CHARACTERISTICS

Symbols and parameters		Units	Values	Conditions	
ON-STATE					
V_{TM}	Peak on-state voltage, max	V	1.80	$T_j=25\text{ }^{\circ}\text{C}$; $I_{TM}=5024\text{ A}$	
$V_{T(TO)}$	On-state threshold voltage, max	V	0.85	$T_j=T_{j\text{ max}}$;	
r_T	On-state slope resistance, max	$\text{m}\Omega$	0.185	$0.5\pi I_{TAV} < I_T < 1.5\pi I_{TAV}$	
I_L	Latching current, max	mA	1500	$T_j=25\text{ }^{\circ}\text{C}$; $V_D=12\text{ V}$; Gate pulse: $I_G=2\text{ A}$; $t_{GP}=50\text{ }\mu\text{S}$; $di_G/dt\geq 1\text{ A}/\mu\text{S}$	
I_H	Holding current, max	mA	300	$T_j=25\text{ }^{\circ}\text{C}$; $V_D=12\text{ V}$; Gate open	
BLOCKING					
I_{DRM} , I_{RRM}	Repetitive peak off-state and Repetitive peak reverse currents, max	mA	150	$T_j=T_{j\text{ max}}$; $V_D=V_{DRM}$; $V_R=V_{RRM}$	
$(dv_D/dt)_{crit}$	Critical rate of rise of off-state voltage ¹⁾ , min	V/ μS	1000	$T_j=T_{j\text{ max}}$; $V_D=0.67\cdot V_{DRM}$; Gate open	
TRIGGERING					
V_{GT}	Gate trigger direct voltage, max	V	2.50 2.00	$T_j=25\text{ }^{\circ}\text{C}$ $T_j= T_{j\text{ max}}$	$V_D=12\text{ V}$; $I_D=3\text{ A}$; Direct gate current
I_{GT}	Gate trigger direct current, max	mA	250 200	$T_j= 25\text{ }^{\circ}\text{C}$ $T_j= T_{j\text{ max}}$	
V_{GD}	Gate non-trigger direct voltage, min	V	0.25	$T_j=T_{j\text{ max}}$; $V_D=0.67\cdot V_{DRM}$; Direct gate current	
I_{GD}	Gate non-trigger direct current, min	mA	10.00		
SWITCHING					
t_{gd}	Delay time	μS	2.00	$T_j=25\text{ }^{\circ}\text{C}$; $V_D=0.4\cdot V_{DRM}$; $I_{TM}=I_{TAV}$; Gate pulse: $I_G=2\text{ A}$; $t_{GP}=50\text{ }\mu\text{S}$; $di_G/dt\geq 1\text{ A}/\mu\text{S}$	
t_q	Turn-off time ²⁾ , max	μS	160	$dv_D/dt=50\text{ V}/\mu\text{S}$; $T_j=T_{j\text{ max}}$; $I_{TM}=2000\text{ A}$; $di_R/dt=-10\text{ A}/\mu\text{S}$; $V_R=100\text{V}$; $V_D=0.67\cdot V_{DRM}$	
Q_{rr}	Total recovered charge, max	μC	2400	$T_j= T_{j\text{ max}}$; $I_{TM}=2000\text{ A}$;	
t_{rr}	Reverse recovery time, max	μS	28.0	$di_R/dt=-10\text{ A}/\mu\text{S}$;	
I_{rrM}	Peak reverse recovery current, max	A	170	$V_R=100\text{ V}$	

THERMAL					
R _{thjc}	Thermal resistance, junction to case, max	°C/W	0.0180	Direct current	Double side cooled
R _{thjc-A}			0.0396		Anode side cooled
R _{thjc-K}			0.0324		Cathode side cooled
R _{thck}	Thermal resistance, case to heatsink, max	°C/W	0.0040	Direct current	
MECHANICAL					
w	Weight, typ	g	510		
D _s	Surface creepage distance	mm (inch)	31.60 (1.244)		
D _a	Air strike distance	mm (inch)	16.50 (0.649)		

OVERALL DIMENSIONS



KT55

All dimensions in millimeters

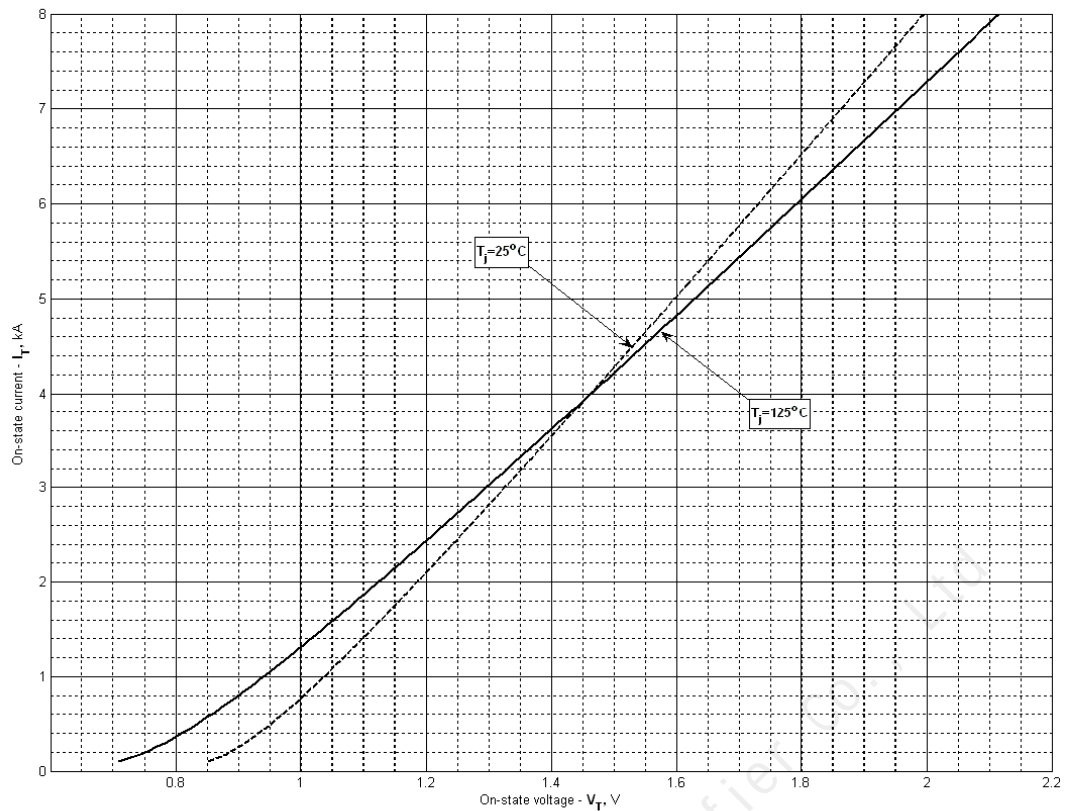


Fig 1 – On-state characteristics of Limit device

Analytical function for On-state characteristic:

$$V_T = A + B \cdot i_T + C \cdot \ln(i_T + 1) + D \cdot \sqrt{i_T}$$

	Coefficients for max curves	
	$T_j = 25^\circ\text{C}$	$T_j = T_{j\text{max}}$
A	0.764304	0.591211
B	0.097013	0.114615
C	-0.186669	-0.249310
D	0.305434	0.407929

On-state characteristic model (see Fig. 1)

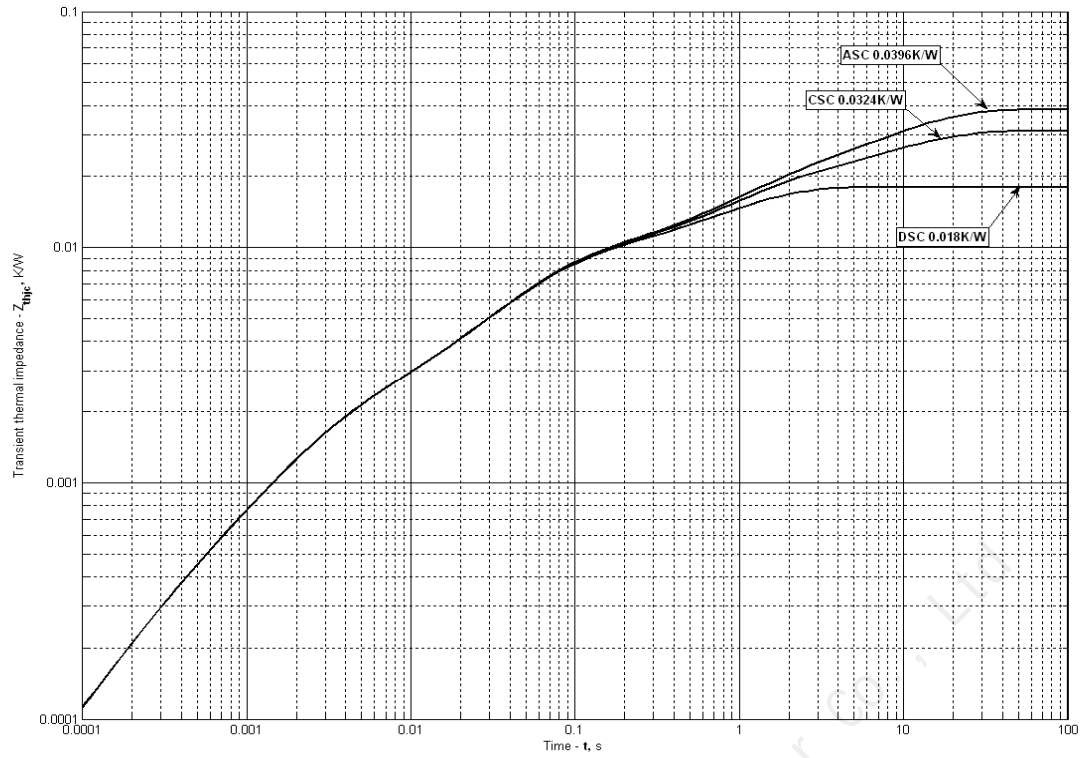


Fig 2 – Transient thermal impedance

Analytical function for Transient thermal impedance junction to case Z_{thjc} for DC:

$$Z_{thjc} = \sum_{i=1}^n R_i \left(1 - e^{-\frac{t}{\tau_i}} \right)$$

Where $i = 1$ to n , n is the number of terms in the series.

t = Duration of heating pulse in seconds.

Z_{thjc} = Thermal resistance at time t .

R_i = Amplitude of p_{th} term.

τ_i = Time constant of r_{th} term.

DC Double side cooled

i	1	2	3	4	5	6
R_i , K/W	0.009241	0.006037	0.001231	0.001054	0.0003396	0.00009575
τ_i , s	0.9673	0.04967	0.002733	0.07734	0.001638	0.0002248

DC Cathode side cooled

i	1	2	3	4	5	6
R_i , K/W	0.01318	0.009281	0.006055	0.001018	0.001535	0.0001182
τ_i , s	9.745	1.028	0.05591	0.03732	0.002468	0.0002687

DC Anode side cooled

i	1	2	3	4	5	6
R_i , K/W	0.02041	0.009325	0.006949	0.0001252	0.001516	0.0001119
τ_i , s	9.752	1.065	0.05344	0.01407	0.002421	0.0002554

Transient thermal impedance junction to case Z_{thjc} model (see Fig. 2)

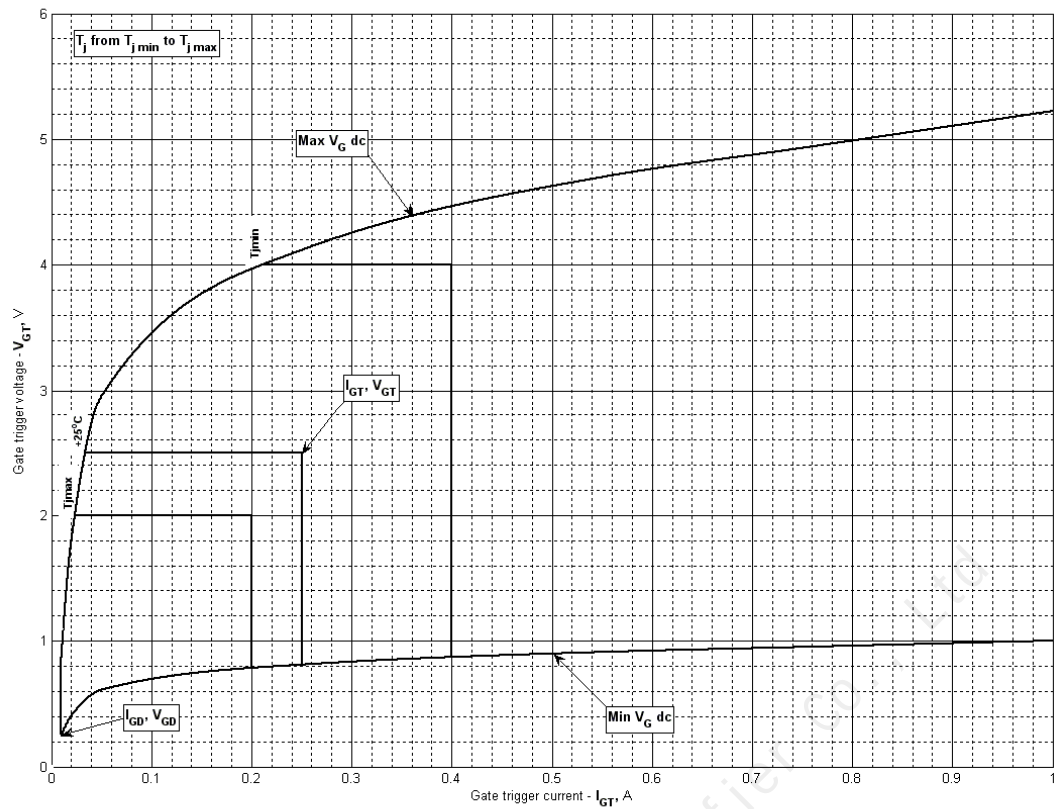


Fig 3 – Gate characteristics – Trigger limits

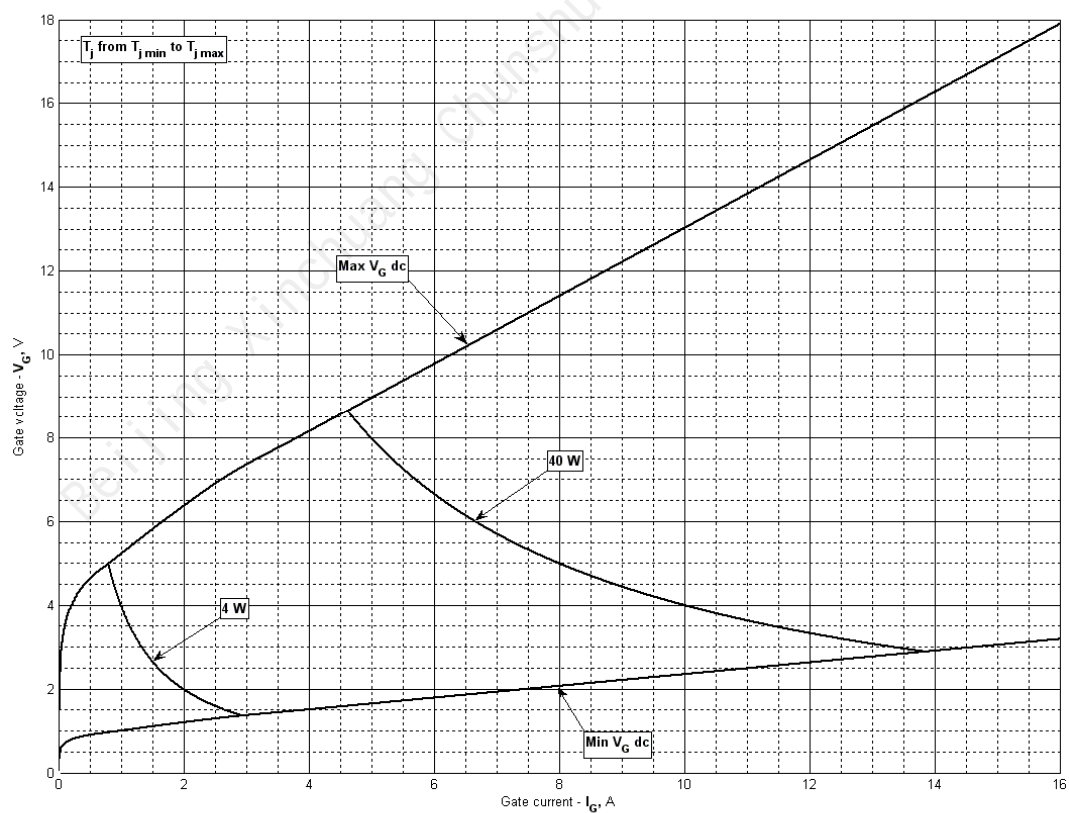


Fig 4 - Gate characteristics –Power curves

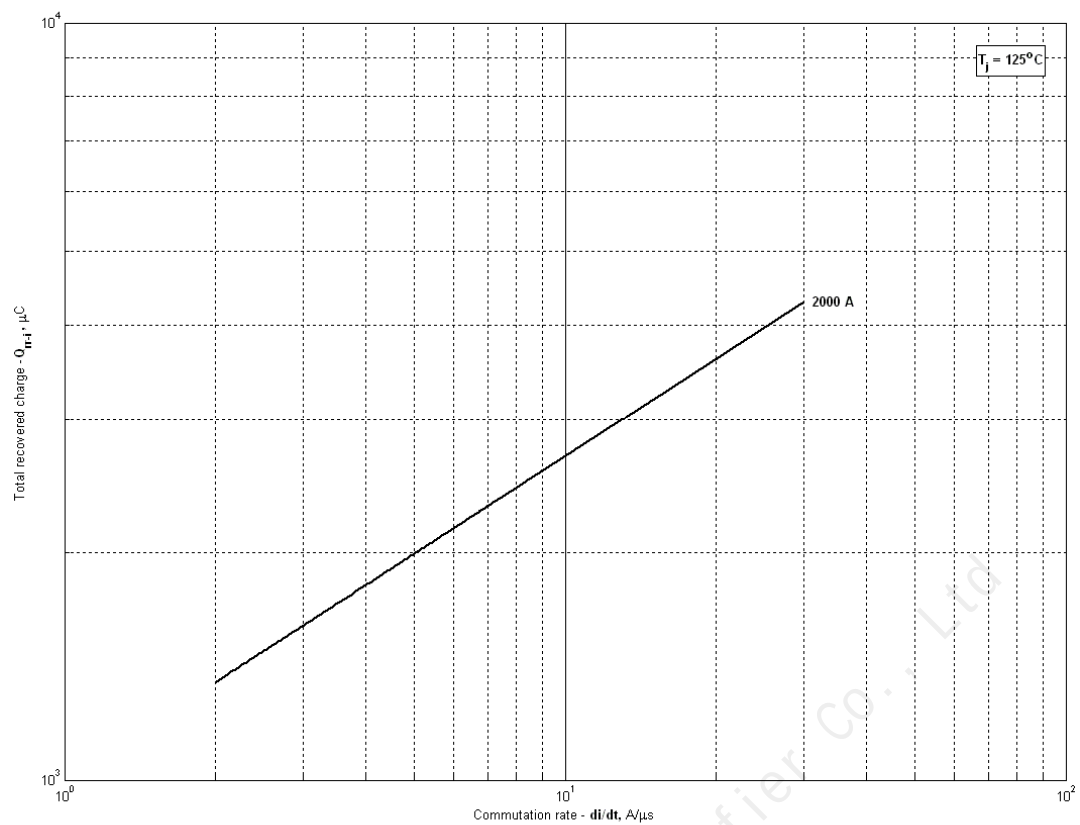


Fig 5 – Total recovered charge, Q_{rr-i} (integral)

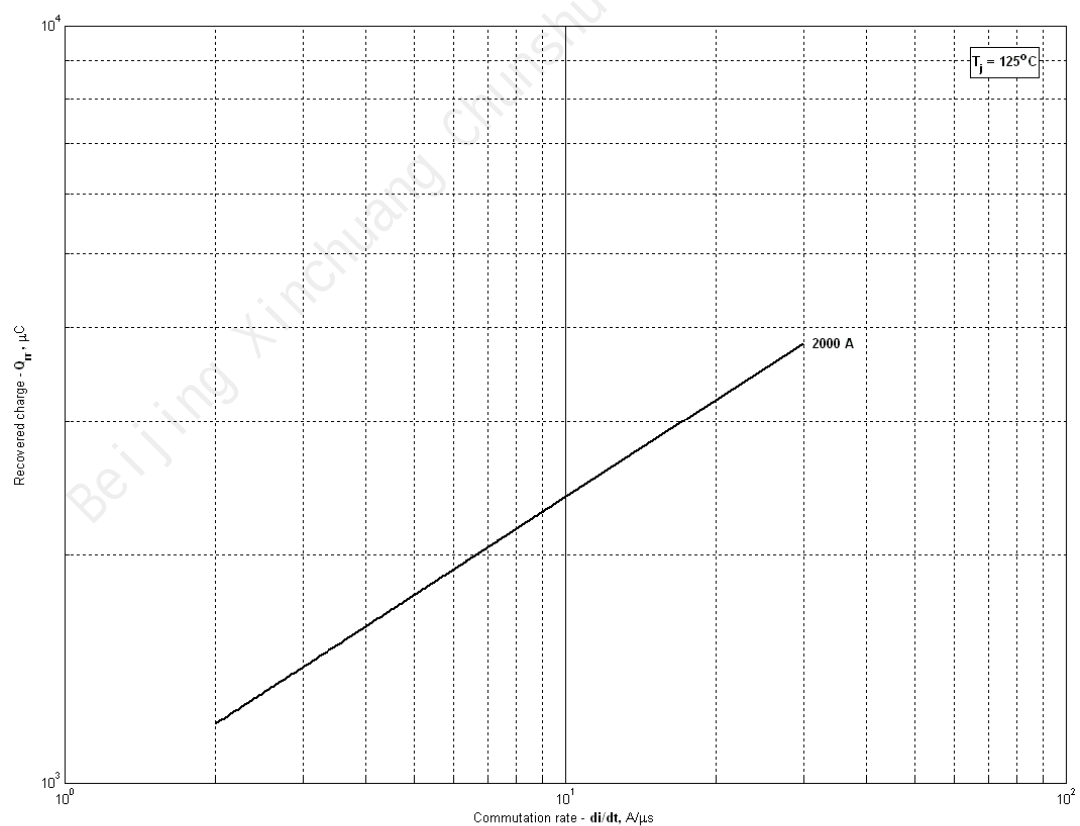


Fig 6 - Recovered charge, Q_{rr} (linear)

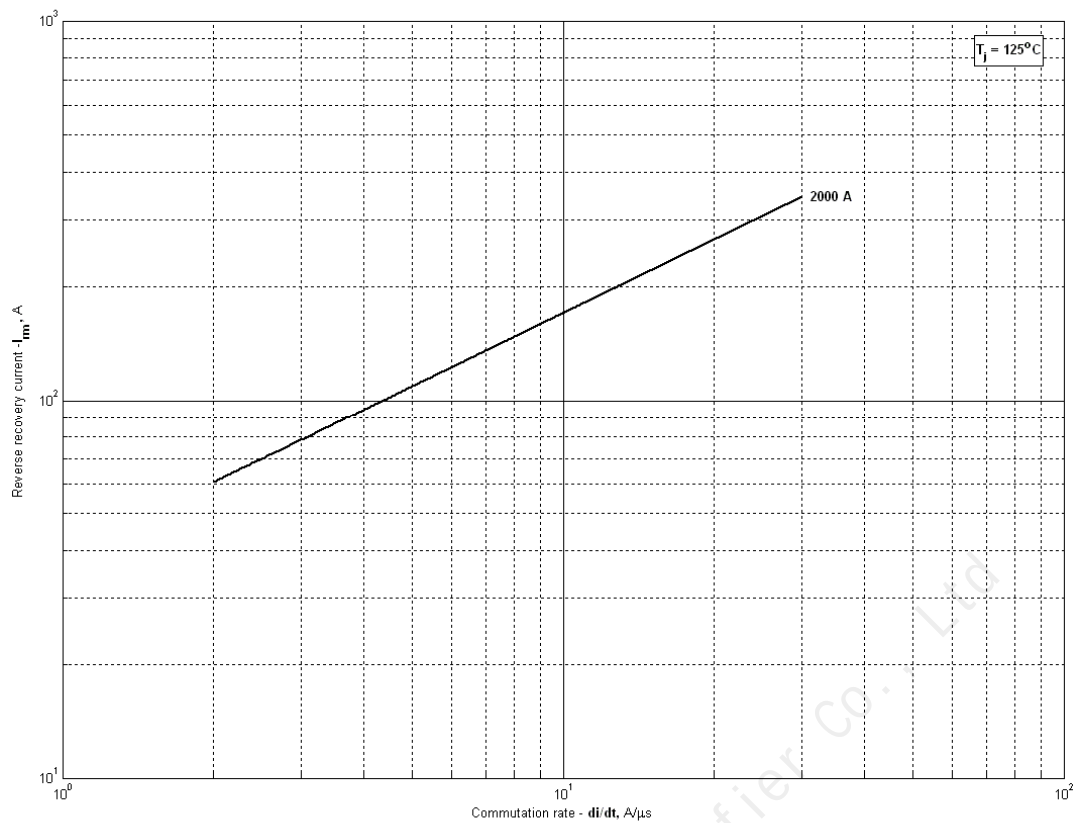


Fig 7 – Peak reverse recovery current, I_{rm}

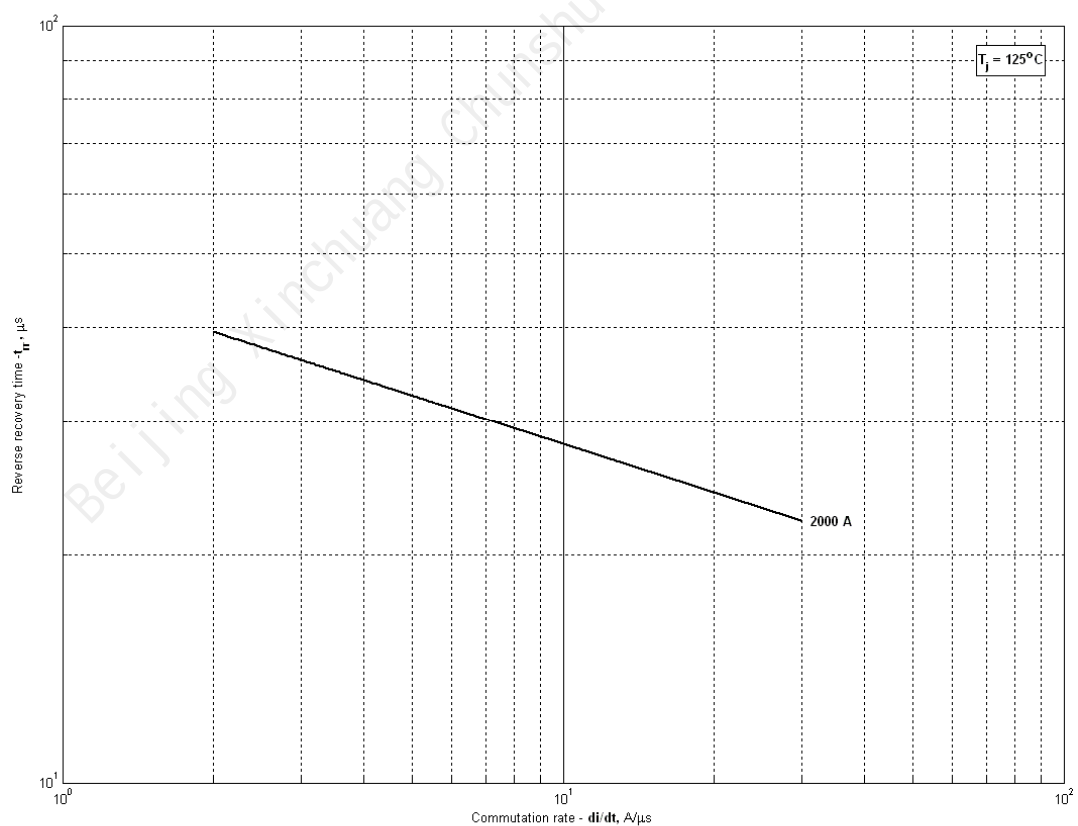


Fig 8 – Maximum recovery time, t_{rr} (linear)

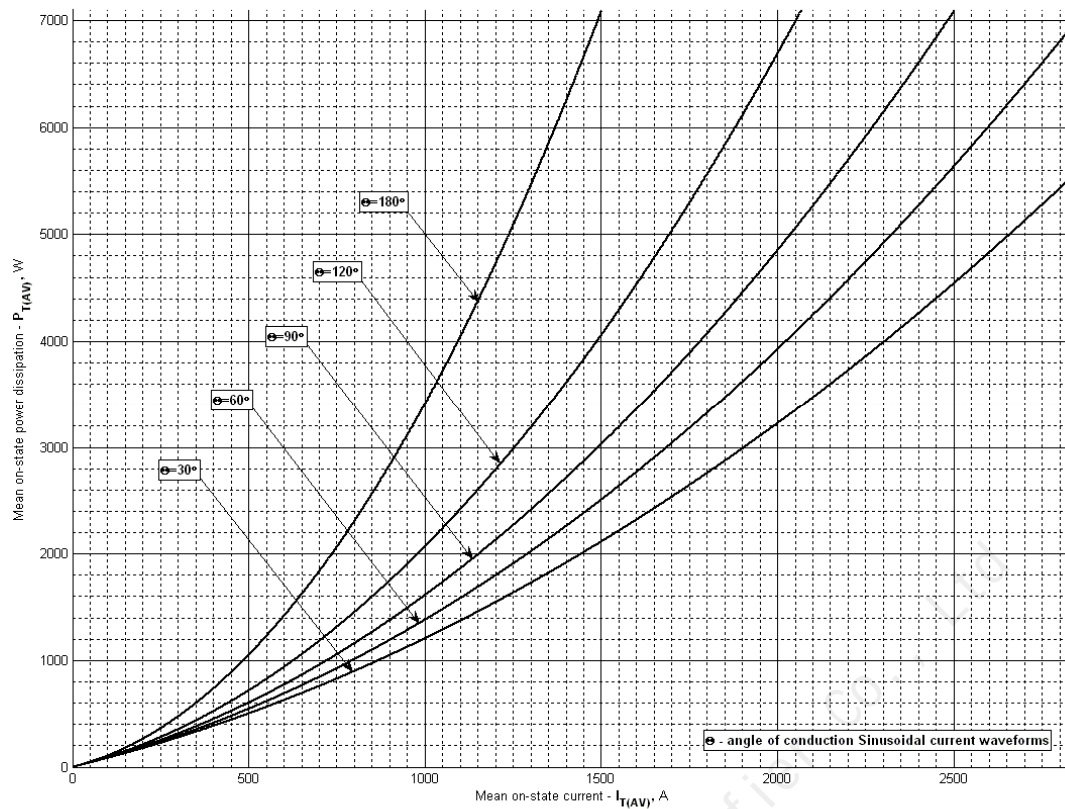


Fig 9 – On-state power loss (sinusoidal current waveforms)

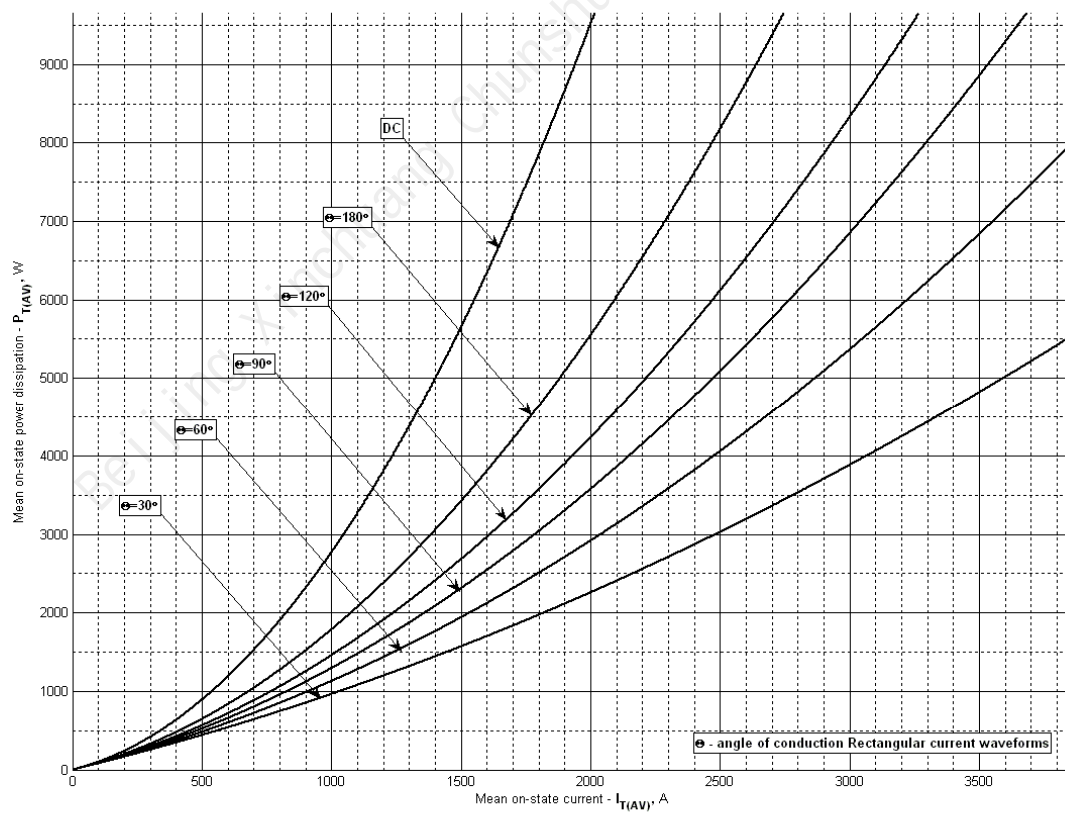


Fig 10 – On-state power loss (rectangular current waveforms)

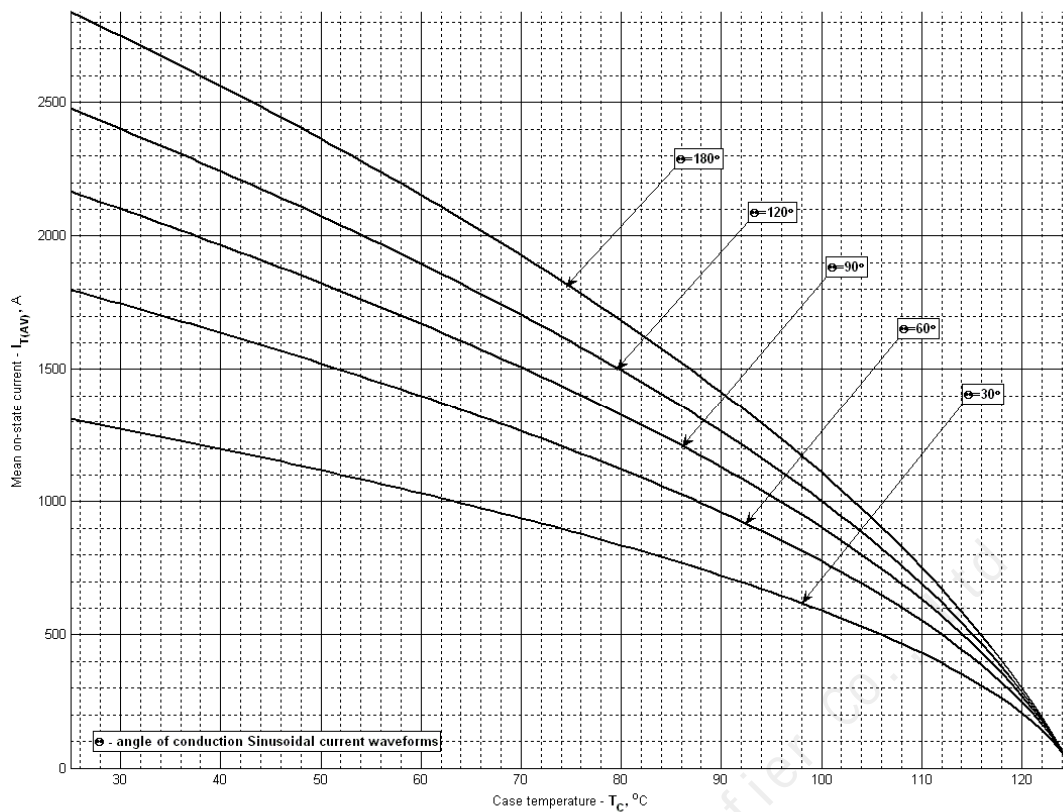


Fig 11 – Maximum case temperature DSC (sinusoidal current waveforms)

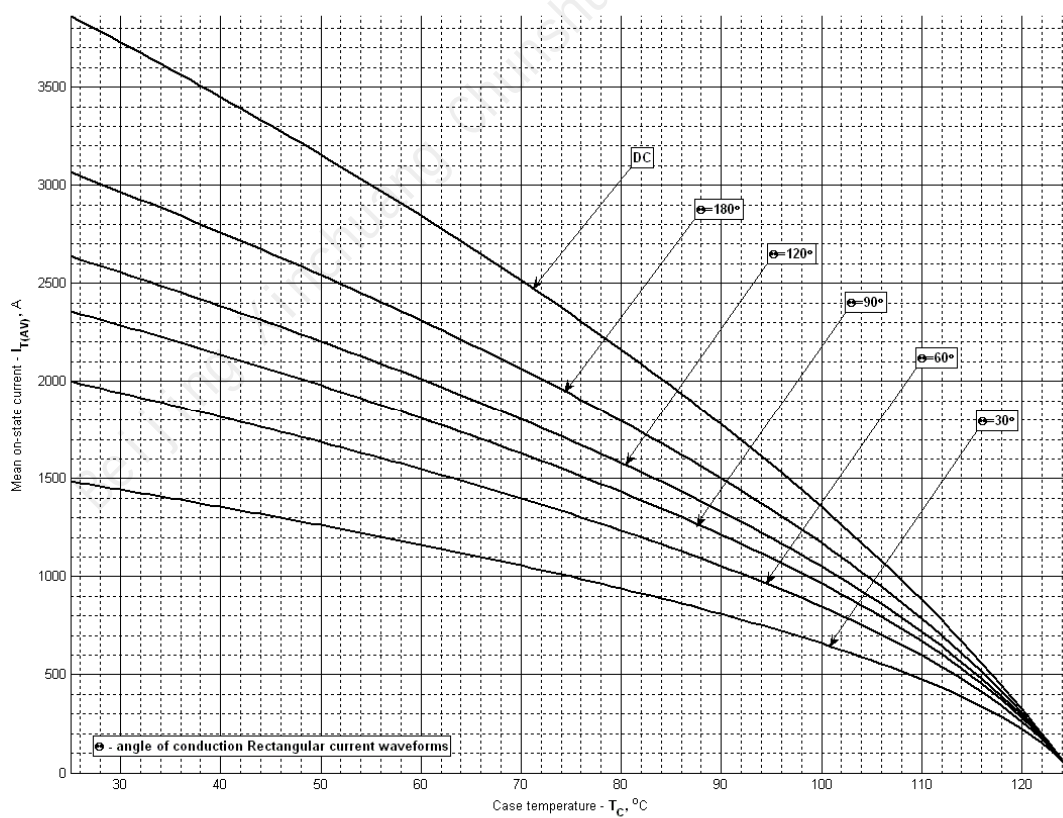


Fig 12 – Maximum case temperature DSC (rectangular current waveforms)

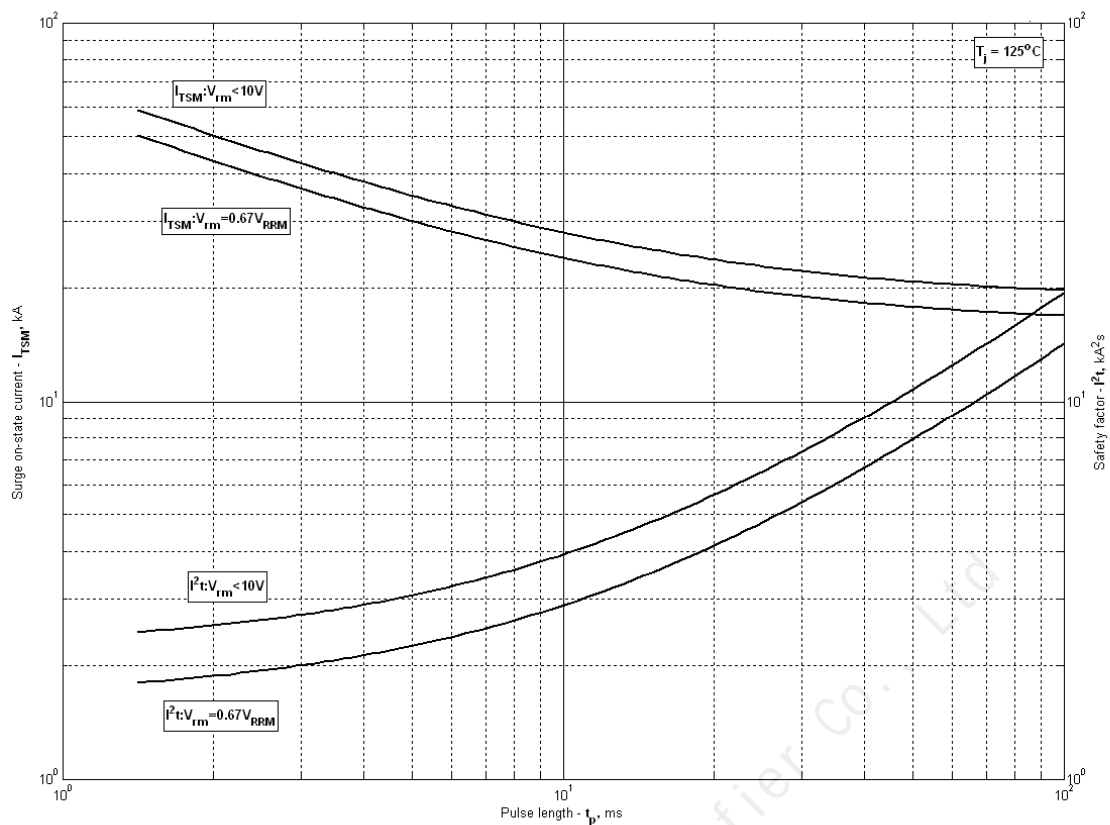


Fig 13 – Maximum surge and I^2t ratings

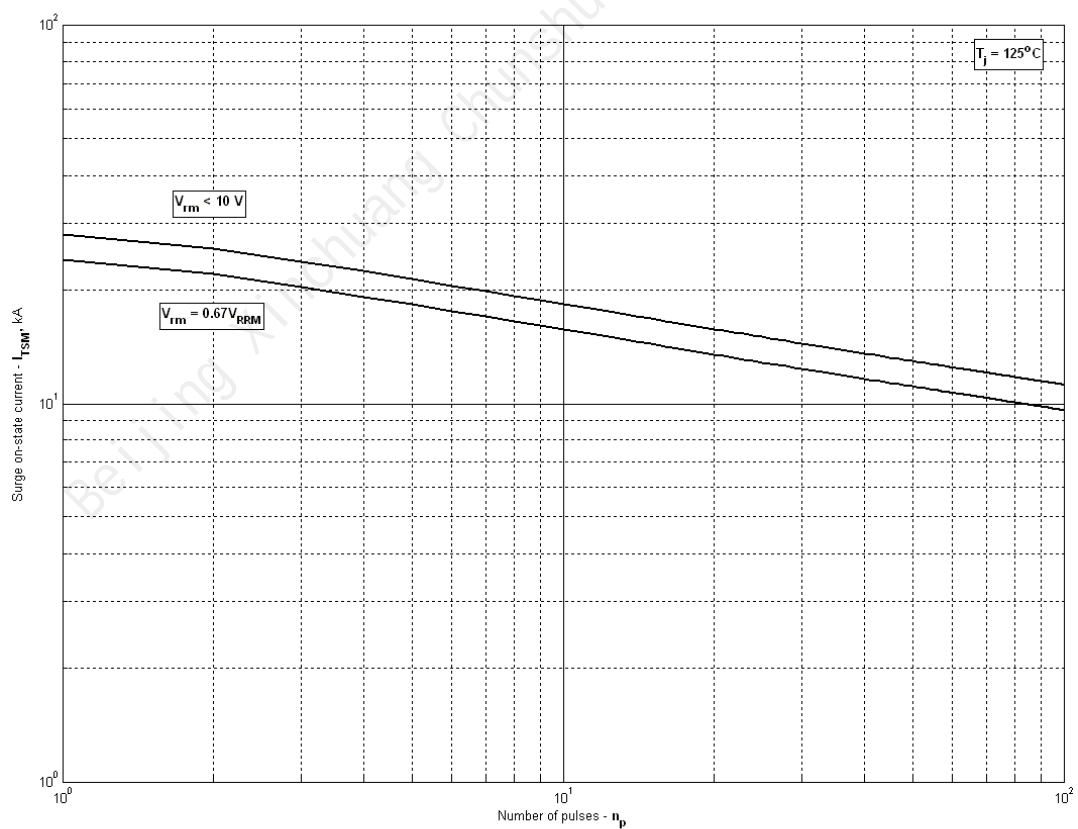


Fig 14 – Maximum surge ratings